

FORM PTO-1449 (modified)
To: U.S. Department of Commerce
(PW FORM PAT-1449)
Patent and Trademark Office

Atty.
Dkt. No.

M#

Client Ref.

304500

P-1503.001-US

**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: Steven HANSEN

Appln. No.: TO BE ASSIGNED 10/7/6,439

Filing Date: November 20, 2003

Date: November 20, 2003

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of

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Examiner:

Group Art Unit:

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AM	AR 5,305,054	04/1994	SUZUKI et al.			
AM	BR 6,049,660	04/2000	AHN et al.			
AM	CR 6,452,662	09/2002	MULKENS et al.			
AM	DR 6,466,304	10/2002	SMITH			
	ER					
	FR					
	GR					
	HR					
	IR					
	JR					
	KR					
	LR					
	MR					
	NR					

FOREIGN PATENT DOCUMENTS

ORIGINAL FILE DOCUMENTS							Abstract		Readily Available	
		Document Number	Date MM/YYYY	Country	Inventor Name		Enclosed	No	Enclose	No
	OR									
	PR									
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OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

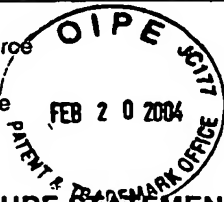
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AAR				
BBR				
CCR				
DDR				

Examiner Alan Matthews

Date Considered: 8-5-2005

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: Steven HANSEN

Appln. No.: 10/716,439

Filing Date: November 20, 2003

Date: February 20, 2004

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Examiner:

Group Art Unit:

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AM	AR 5,523,193	06/1996	NELSON			
AM	BR 6,463,403 B1	10/2002	BURDORF et al.			
AM	CR 2002/0035461 A1	03/2002	CHANG et al.			
AM	DR 2002/0045106 A1	04/2002	BASELMANS et al.			
AM	ER 2002/0062206 A1	05/2002	LIEBCHEN			
AM	FR 2002/0152452 A1	10/2002	SOCHA			
AM	GR 2002/0167653 A1	11/2002	MULKENS et al.			
AM	HR 2003/0093251 A2	05/2003	CHANG			
	IR					
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FOREIGN PATENT DOCUMENTS

	Document Number	Date MM/YYYY	Country	Inventor Name		English Abstract		Translation Readily Available	
						Enclosed	No	Enclose	No
	OR								
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Examiner Alan Mathews

Date Considered: 8-6-2005

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	304500	P-1503.001-US

**INFORMATION DISCLOSURE STATEMENT
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Applicant: HANSEN	
Appln. No.: 10/716,439	
Filing Date: November 20, 2003	
Examiner: NOT ASSIGNED	Group Art Unit: 2825 2851

Date: May 10, 2004 Page 1 of 1

U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AM	AR 5,680,588	10/1997	Gortych et al.			
AM	BR 2003/0082463 A1	05/2003	Laidig et al.			

FOREIGN PATENT DOCUMENTS

		Document Number	Date MM/YYYY	Country	Inventor Name		Abstract		Readily Available	
							Enclosed	No	Enclose	No
	CR									

OTHER (Including in this order Author, Title, Periodical Name, Date, Pertinent Pages, etc.)

AM	DR	Burkhardt et al., "Illuminator Design for the Printing of Regular Contact Patterns," <i>Microelectronic Engineering</i> , Vol. 41, No. 42, 1998, pp. 91-96.			
	ER	Chen et al., "Practical Method for Full-Chip Optical Proximity Correction," <i>SPIE</i> , Vol. 3051, 1997, pp. 790-803.			
	FR	Chen et al., "Optical Proximity Correction for Intermediate-Pitch Features Using Sub-Resolution Scattering Bars," <i>Journal of Vacuum Science & Technology B</i> , Vol. 15, No. 6, Nov/Dec 1997, pp. 2426-2433.			
	GR	Flagello et al., "Lithographic Lens Testing: Analysis of Measured Aerial Images, Interferometric Data and Photoresist Measurements," <i>SPIE Microlithography Seminar</i> , 1996.			
	HR	Flagello et al., "Towards a Comprehensive Control of Full-Field Image Quality in Optical Photolithography," <i>SPIE Microlithography Seminar</i> , March 1997.			
	IR	Gau et al., "Strategy to Manipulate the Optical Proximity Effect by Post-Exposure Bake Processing," <i>SPIE</i> , Vol. 3334, 1998, pp. 885-891.			
	JR	Gau et al., "The Customized Illumination Aperture Filter for Low k1 Photolithography Process," <i>SPIE</i> , Vol. 4000, March 2000, pp. 271-282.			
	KR	Hsia et al., "Customized Off-Axis Illumination Aperture Filtering for Sub-0.18 μ m KrF Lithography," <i>SPIE</i> , Vol. 3679, March 1999, pp. 427-434.			
	LR	Liu et al., "The Application of Alternating Phase-Shifting Masks to 140 nm Gate Patterning: Line Width Control Improvements and Design Optimization," <i>SPIE</i> , Vol. 3236, 1998, pp. 328-337.			
	MR	Smith et al., "Illumination Pupil Filtering Using Modified Quadrupole Apertures," <i>SPIE</i> , Vol. 3334, 1998, pp. 384-394.			
	NR	Suzuki et al., "Multilevel Imaging System Realizing $k_1=0.3$ Lithography," <i>SPIE</i> , Vol. 3679, March 1999, pp. 396-407.			
✓	OR	Wong et al., "Level-Specific Lithography Optimization for 1-Gb DRAM," <i>IEEE Transactions on Semiconductor Manufacturing</i> , Vol. 13, No. 1, February 2000, pp. 76-87.			

Examiner Alan Mathews Date Considered: 8-5-2005

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HANSEN - 10/716,439
Docket No. 081468-0304500



APPENDIX

Examiner's Initials	First Inventor	Application No.	Filing Date	Enclosed
AM	Liebchen	10/705,234	November 12, 2003	<input checked="" type="checkbox"/> Specification <input checked="" type="checkbox"/> Drawings <input checked="" type="checkbox"/> Other: Claims

The Examiner's initials indicates he/she has considered the cited application relative to the subject application.

DO NOT PRINT the above information on the patent which results from the subject application.

Alan A. Mathews

Date Considered
8-5-2005

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To: U.S. Department of Commerce
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P-1503.010-US

Applicant: HANSEN

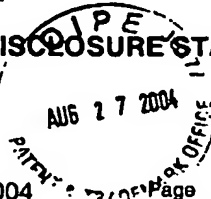
Appln. No.: 10/716,439

Filing Date: November 20, 2003

Examiner: TBA

Group Art Unit: 2825

INFORMATION DISCLOSURE STATEMENT BY APPLICANT



Date: August 27, 2004

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U.S. PATENT DOCUMENTS

Examiner's Initials*	Document Number	Date MM/YYYY	Name (Family Name of First Inventor)	Class	Sub Class	Filing Date (if appropriate)
AM	AR 2003/0073013 A1	04/2003	Hsu et al.			
	BR					
	CR					
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